

# **MOSFET** – Power, N-Channel, UltraFET

55 V, 15 A, 90 mΩ

## **FDMC15N06**

#### Description

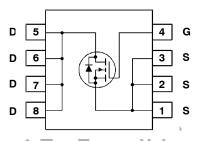
These N-Channel power MOSFETs are manufactured using the innovative UItraFET process. This advanced process technology achieves the lowest possible on-resistance per silicon area, resulting in outstanding performance.

This device is capable of withstanding high energy in the avalanche mode and the diode exhibits very low reverse recovery time and stored charge. It was designed for use in applications where power efficiency is important, such as switching regulators, switching converters, motor drivers, relay drivers, low voltage bus switches, and power management in portable and battery-operated products.

#### **Features**

- THIS DEVICE PLEASENTATIVE FOR PREPRESENTATIVE PREPRESENTATIVE •  $R_{DS(on)} = 75 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$
- 100% Avalanche Tested
- These Device is Pb-Free and RoHS Compliant





## MARKING DIAGRAM



Assembly Plant Code = Assembly Figure 321 = Date Code (Year & Week) = Lot Traceability Code 15N06 + Specific Device Code

## ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
FDMC15N06	WDFN8 (Pb-Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### **MOSFET MAXIMUM RATINGS** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Unit
V <sub>DSS</sub>	Drain to Source Voltage	55	V
V <sub>GSS</sub>	Gate to Source Voltage	±20	V
I <sub>D</sub>		15 9 2.4	А
I <sub>DM</sub>	Drain Current -Pulsed (Note 2)	60	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 3)	36	mJ
I <sub>AR</sub>	Avalanche Energy	15	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	3.5	mJ
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C) (T <sub>A</sub> = 25°C)	35 S G	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max	3.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max (Note 1)	53	

## **ELECTRICAL CHARACTERISTICS** To = 25 °C unless otherwise noted.

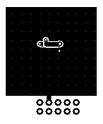
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
Off Characteristics							
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D$ = 250 $\mu$ A, $V_{GS}$ = 0 V, $T_C$ = 25 $^{\circ}$ C	55	-	_	V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C	-	70	-	V/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 50 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = 45 V, T <sub>C</sub> = 150 °C	- -	_ _	1 250	μΑ	
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA	
On Characteris	stics						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	-	4.0	V	
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 15 A	-	0.075	0.090	Ω	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 15 A	-	5	_	S	
Dynamic Chara	acteristics						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	265	350	pF	
C <sub>oss</sub>	Output Capacitance	]	-	97	130	pF	
C <sub>rss</sub>	Reverse Transfer Capacitance	1	-	28	42	pF	
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 15 A,	-	8.8	11.5	nC	
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>GS</sub> = 10 V (Note 4)	-	1.7	_	nC	
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	3.6	_	nC	

### **ELECTRICAL CHARACTERISTICS** Tc = 25 °C unless otherwise noted.(continued)

		\ /				
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Switching Ch	naracteristics		•	-		
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 30 \text{ V}, I_D = 15 \text{ A},$	-	9.5	29	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_G = 25 \Omega \text{ (Note 4)}$	-	36.5	83	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		-	22.5	55	ns
t <sub>f</sub>	Turn-Off Fall Time		-	22	54	ns
rain-Source	e Diode Characteristics					
I <sub>S</sub>	Maximum Continuous Drain to Source	-	-	_	15	Α
	Diode Forward Current		-	-	60	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	1.25	V
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 15 A				7
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{SD} = 15 \text{ A},$	-	30	CIO.	ns
$Q_{rr}$	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs (Note 5)	1	35	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. R<sub>0.1A</sub> is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material R<sub>0.1C</sub> is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



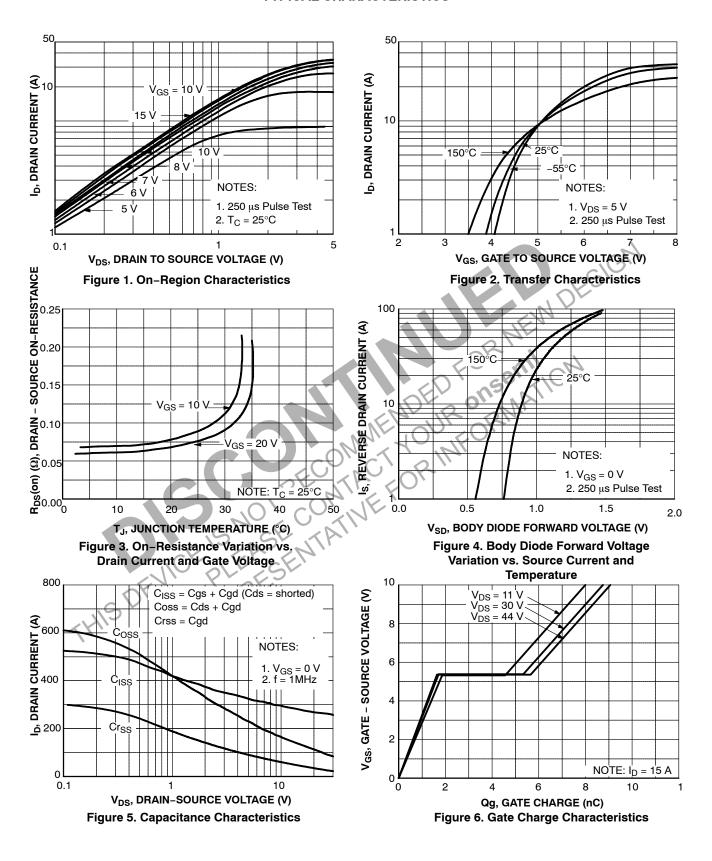
a. 53 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper

b.125 °C/W when mounted on a minimum pad of 2 oz copper



- 2. Repetitive rating: pulse-width limited by maximum junction temperature.
- 3. L = 1 mH,  $I_{AS}$  = 8.5 A,  $R_{G}$  = 25  $\Omega$ , starting TJ = 25 °C. 4. Essentially independent of operating temperature typical characteristics. THIS DEVICE PRESENT.
- 5.  $I_{SD} \le 15$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le 40$  V, starting  $T_J = 25^{\circ}$ C.

#### **TYPICAL CHARACTERISTICS**



#### TYPICAL CHARACTERISTICS (CONTINUED)

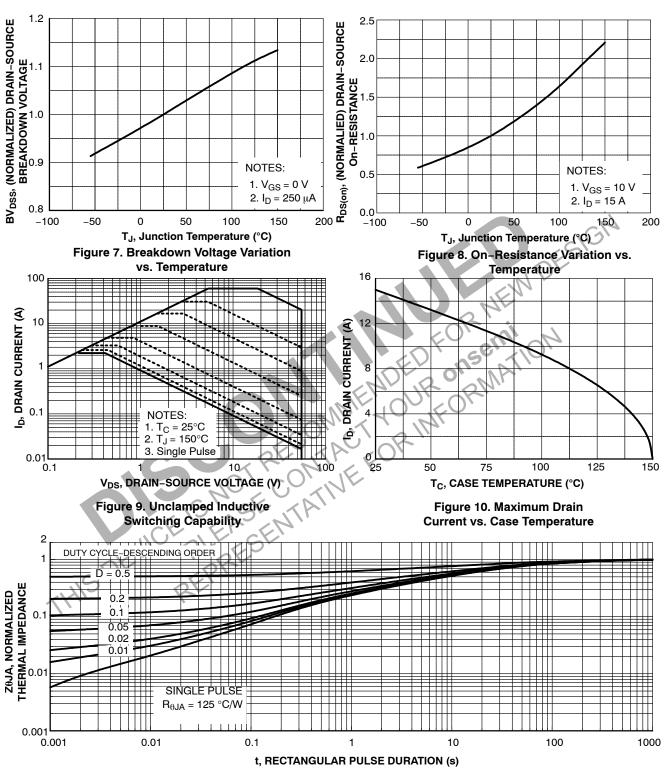


Figure 11. Thermal Response Curve

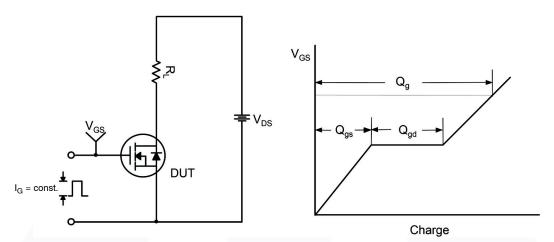


Figure 12. Gate Charge Test Circuit & Waveform

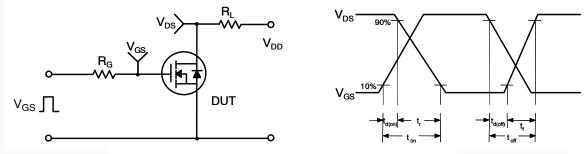


Figure 13. Resistive Switching Test Circuit & Waveforms

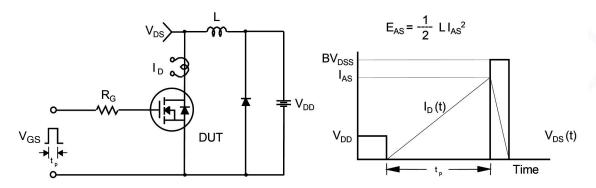


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

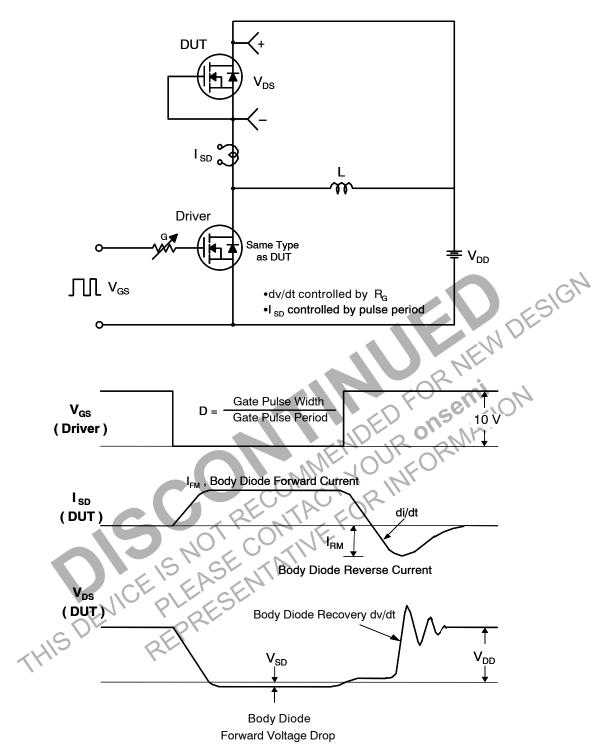
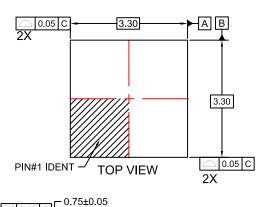
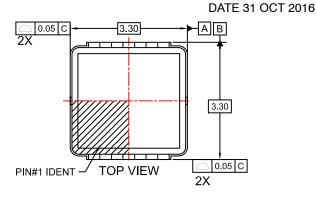


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

## WDFN8 3.3x3.3, 0.65P CASE 511DQ

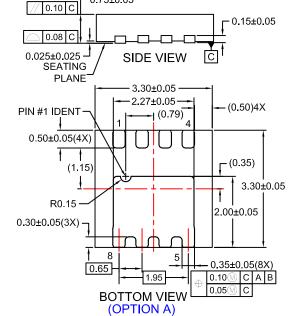
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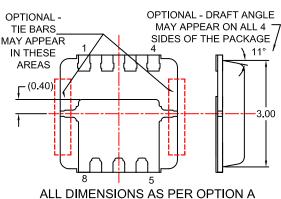


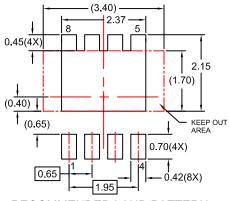


3.20

SIDE VIEW







UNLESS SPECIFIED **BOTTOM VIEW** (OPTION B)

RECOMMENDED LAND PATTERN

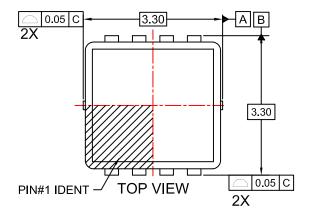
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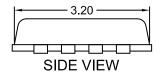
**DESCRIPTION:** WDFN8 3.3X3.3, 0.65P PAGE 1 OF 2

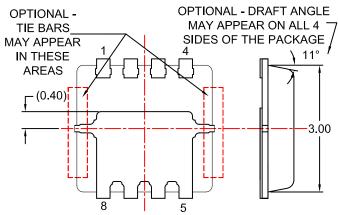
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**DATE 31 OCT 2016** 







ALL DIMENSIONS AS PER OPTION A
UNLESS SPECIFIED
BOTTOM VIEW
(OPTION C)

#### NOTES:

- A. PACKAGE DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-240.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN
- E. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. BURRS OR MOLD FLASH SHALL NOT EXCEED 0.10MM.

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